Control of interlayer exchange coupling in Fe/Cr/Fe trilayers by ion beam irradiation

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The manipulation of the antiferrom agnetic interlayer coupling in the epitaxial Fe/C r/Fe (001) trilayer system by moderate 5 keV. He ion beam irradiation has been investigated experimentally. It is shown that even for irradiation with very low—uences $(10^{14} \text{ ions/cm}^2)$ a drastic change in strength of the coupling appears. For thin C r-spacers (below 0.6 { 0.7 nm}) the coupling strength decreases with uence, becoming ferrom agnetic for uences above $(2 \cdot 10^{14} \text{ ions/cm}^2)$. The elect is connected with the creation of magnetic bridges in the layered system due to atom ic exchange events caused by the bom bardment. For thicker C r spacers (0.8 + 1.2 nm) an enhancement of the antiferrom agnetic coupling strength is found. A possible explanation of the enhancement extra given.

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Since the discovery of the antiferrom agnetic interlayer exchange coupling e ect in the Fe/C r/Fe layered system by Grunberg et al. [1] this e ect has been widely investigated both theoretically and experim entally (for a recent review see [2]). A ntiferrom agnetically coupled layers are now used in applications like antiferrom agnetically coupled m edia (AFC-m edia [3]) and articial antiferrom agnets, (AAF [4]). In many cases such applications greatly gain from a potential of lateral modi cation of the media param eters with high resolution, after the preparation process of the layered system has been completed. It is not trivial to change the interlayer coupling strength after sam ple preparation. Until now, to our know ledge, the only reported m ethods are annealing [5] and charging of the spacer with hydrogen or deuterium [6,7,8]. However, such techniques can hardly provide any reasonable lateral resolution. On the contrary, beam soflight ions with keV energies known for their ability to deeply penetrate into a solid can be focused down to 20 nm [9, 10, 11], and should provide a promising pass to accomplish the goal. One of the key advantages of ion irradiation is that magnetic nanopatteming becomes feasible without a change of the sam ple topography. This is especially important to avoid tribology problems in so-called patterned media [12].

In this Letter, we present rst experimental results demonstrating that the strength of the interlayer exchange coupling between two ferrom agnets, separated by a non-ferrom agnetic spacer, can be modiled in a controlled manner by ion beam irradiation. It is also shown, that for some values of the spacer thickness the ion beam

bom bardm ent enhances the coupling.

Interaction between two magnetic layers separated by a nonmagnetic spacer layer can be phenomenologically described by:

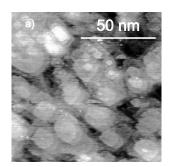
$$E = J_1 \cos J_2 \cos^2$$

where E is the magnetic coupling interface energy, is the angle between the magnetizations of two magnetic layers and the param eters J_1 and J_2 represent the strength of the bilinear and biquadratic coupling, respectively [13]. If J_2 dom in at and is negative, it promotes perpendicular (90) orientation of the two magnetization vectors. The microscopic origin of the bilinear coupling is a long-range interaction between the magnetic moments via conduction electrons of the spacer. For smooth interfaces J₁ oscillates as a function of the spacer thickness [14, 15]. Essential roughness dim in ishes the bilinear coupling strength and the amplitude of the oscillations [16, 17]. For perfect layered system s J_2 is thought to be small [18]. The experimentally observed strong biquadratic coupling is believed to be due to extrinsic effects [19, 20].

Light ion irradiation is known to be an excellent tool to modify magnetic parameters of multilayer systems. Chappert et al. [21] have shown that ion irradiation of Co/Ptmultilayers leads to a reduction of the perpendicular interface anisotropy. This has been attributed to an interfacial mixing of both atom species. In FePt alloy systems an increase of the perpendicular magnetic anisotropy due to a short range chemical ordering has been observed after ion irradiation [22]. The technique

has been recently applied to exchange bias system s, consisting of adjacent ferrom agnetic and antiferrom agnetic layers. It was shown that the magnitude and direction of the exchange bias eld can be tailored by ion irradiation if a magnetic eld is applied during bom bardment [23, 24].

Epitaxial Fe/Cr/Fe(001) samples used in the current studies were prepared in an ultra high vacuum molecularbeam epitaxy system with the base pressure below 5 10 11 mbar. A Crbu erwith a thickness of 100 nm providing a lattice matched template for the subsequent growth of the Fe/Cr/Fe [26] system was deposited on a MgO (001) substrate. Two Fe Ims separated by an wedge-shape, 0.4 to 4 nm thick Crspacerwere deposited on the bu er. Dierent samples with the thickness of the Fe Ims from 5 to 10 nm have been prepared. Finally the system was covered by 3 nm Crto avoid corrosion for ex-situ m easurem ents. The details of substrate preparation and the growth procedure are published elsewhere [25]. Figure 1 displays the topography of the lower Fe Im and of the Cr spacer as observed by STM . A tom ic terraces and monoatomic steps are clearly seen in the im ages.



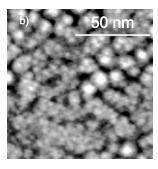


FIG.1:STM images of the lm surfaces:a) bottom Fe lm, z-scale $1.3\,\mathrm{nm}$, RMS = $0.11\,\mathrm{nm}$;b) Crspacer, z-scale $1.5\,\mathrm{nm}$, RMS = $0.18\,\mathrm{nm}$.

U sing the measured RMS values of the surface roughness (0.11 and 0.18 nm for the Fe and the Cr surface, respectively) and assuming uncorrelated thickness uctuations for the two lms, one obtains an RMS value for the thickness uctuations of the Cr spacer of 0.14 nm, which is close to the thickness of one monolayer (ML). Based on this value and assuming a Gaussian distribution of the probability for the spacer to consist of a given number of monolayers, one obtains, for example, for a nominal thickness of the Cr spacer, $d_{\rm Cr}$ of 4 ML that: 38% of the lmarea has $d_{\rm Cr}=4$ ML, 24% has $d_{\rm Cr}=3$ ML, 6% 2 ML, 0.6% 1 ML, and 0.025% corresponds to direct contact between the two Fe lms (so-called "magnetic bridges"). The latter provide a strong ferrom agnetic coupling between the Fe lms.

Irradiation was performed with $5\,\mathrm{keV}$ He $^+$ ions without applied magnetic eld with the sample being kept at room temperature. TRIM simulations [27] show that for the used parameter set most ions pass both magnetic layers and are stoped in the Crbu er layer. The maximum uence used was $8~10^{14}\,\mathrm{ions/cm}^2$. The interlayer coupling was derived from the magnetization curves recorded by longitudinal magneto-optical Kerre ect (MOKE) magnetometry. A magnetic eld of up to $6\,\mathrm{kO}$ e was applied in the plane of the sample parallel either to the easy or to the hard magnetic axes of the four-fold magnetic anisotropy of the Fe(001) lms.

The magnetization curves measured for the eld applied along the easy [100]-axis show several jum ps, characteristic for magnetic double layers with antiferrom agnetic and 90 -coupling [13]. The saturation $\,$ eld, $\,$ H $_{\rm S}$, which is proportional to $jJ_1 + 2J_2$ jextracted from the magnetization curves is shown in Fig. 2 as a function of the nom inal Cr-spacer thickness for dierent ion irradiation uences. The data obtained on the as-prepared sample clearly demonstrate both long-and short-period oscillations with a moderate amplitude in agreement with the RMS value of the spacer thickness uctuation obtained from the STM studies. The arrows indicate the rst three oscillation maxima of the coupling strength. As it is seen in Fig. 2, such a well prepared layered magnetic system is very sensitive to ion irradiation. The rst oscillation maximum ($d_{Cr} = 0.58 \text{ nm} = 4 \text{ M L}$) exhibits the strongest e ect of the irradiation on the coupling strength. Even the lowest used ion uence of $0.5 10^{14} ions/cm²$ reduced H $_{\rm S}$ nearly by 25%. For the uences above 2 10¹⁴ ions/cm² no antiferrom agnetic coupling is observed for this thickness of the Cr-spacer. The change of the measured coupling strength for thicker Cr-spacers is more intriguing: the coupling increases for small ion uences and then decreases for uences above $10^{14} \text{ ions/cm}^2$ [28].

An additional study made by means of Brillouin light scattering on spin waves has indicated no change in the four-fold in-plane and out-of-plane anisotropy constants after the bom bardment for the studied uence range.

Of particular interest are the dependencies of the coupling constants J_1 and J_2 as functions of ion uence and spacer thickness. From the measured remagnetization curves the uence dependence of those constants for the spacer thicknesses corresponding to the rst (4 M L), second (6 M L), and third (8 M L) oscillation maxima have been evaluated. Note that only the values of the antiferrom agnetic ($J_1 < 0$) and 90 -degree ($J_2 < 0$) coupling constants can be usually derived in such a way. The data is presented in Fig. 3. It is clearly seen from the gure, that jJ_1 jstrongly decreases with the uence for d_{C r}= 4 M L, while it shows a maximum for uences near 0:5 10^{14} ions/cm² for d_{Cr} equal to 6 and 8 M L.jJ₂ j instead shows a monotonic decrease. Thus, one can conclude from Fig. 3 that the increase of the saturation eld at small irradiation uences is caused by the increase of jJ_1 j.

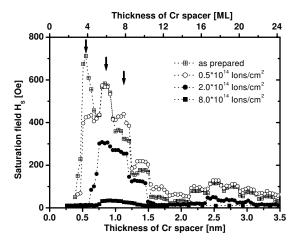


FIG. 2: Saturation eld H $_{\rm S}$ as a function of the Cr spacer thickness for the 10 nm Fe/d_{Cr} Cr/10 nm Fe trilayer system as prepared and after the irradiation with the uences as indicated. The arrows indicate the rst three maxima of the interlayer coupling.

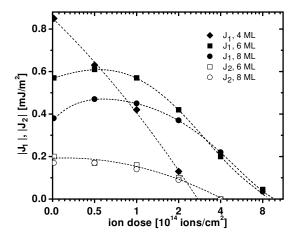


FIG. 3: J_1 and J_2 obtained form the rem agnetization curves for di erent maxima versus the uence. The lines are guides to the eye.

The origin of the observed phenomena is not understood in all details yet, but they are denitely connected with the surface intermixing caused by the He ions. To understand this qualitively let us rst consider the unence dependence of j J_1 j for the nominal thickness $d_{\rm C\,r}=4$ M L.D irect magnetic bridges between the two Fe lm sprovide strong direct ferromagnetic coupling, $J_{\rm direct}$

 $2A=d_{M\ L}=280$ m J/m 2 , where A=2 10^{11} J/m is the bulk exchange constant of Fe and $d_{M\ L}=0.144$ nm is the thickness of one monolayer. The contribution to the measured interlayer coupling due to the magnetic bridges can be then easily estimated, since the percentage area of those bridges is known from the RMS analysis of the STM

im ages discussed above. For the as-prepared sample the obtained value of $0.07\,\mathrm{m}$ J/m 2 is essentially sm aller than the measured one and indicates that the interlayer coupling via the spacer is an order ofm agnitude larger than direct coupling across the bridges.

It is known that an ion propagating within a lattice partly dissipates its energy due to nuclear collisions [27]. Such collisions cause recoil of atom softhe lattice and creation of lattice defects and interm ixing. A lthough light ions, like helium, have a low displacem ent rate and cause a short range interm ixing, these processes are of importance if taking place at the interface. Estimations show that a 5 keV He ion initiates in average between one and two atom pair exchange events per monolayer in Fe and Cr [29]. In the areas with $d_{Cr} = 1 \text{ ML}$ such an exchange event induces an atom ic size magnetic bridge. Assuming that each ion generates one exchange event per monolayer as a lower bond and taking into account also a possibility of two successive exchange events at adjacent lattice sites, one obtains that for the uence of 2 10¹⁴ ions/cm² the relative area of the magnetic bridges increases to 0.2% and their contribution to the interlayer coupling is $0.6 \,\mathrm{m}\,\mathrm{J/m}^2$. This is in rather good agreem ent with the experimentally observed coupling reduction of $0.72 \,\mathrm{m}\,\mathrm{J/m}^2$. The calculation also demonstrates that the probability for form ation of magnetic bridges due to the bom bardm ent decreases exponentially with the nominal spacer thickness at a given interface roughness. Thus, it is not surprising that the e ect of the irradiation is weaker for larger spacer thicknesses (the second and third maximum).

Surprising is, how ever, the observation of an increase of the antiferrom agnetic coupling strength. These ndings might be related to the fact, that, rst, an intermixing at the Fe/C r(001) interface with a width of 1-2 m onolayers is supposed to be energetically favorable [30, 31, 32], but it is usually not completely achieved during the lm growth because of kinetic growth e ects. Second, He ions in the discussed energy range very e ectively transferenergy to phonons (8 { 12 eV perm onolayer), which in turn help the system to relax into this optimum.

It is known that the interlayer coupling in the Fe/C r/Fe (001) layered system can be increased by a gentle annealing [5]. Stronger coupling in this case is usually connected with higher lateral hom ogeneity of interface interm ixing between Fe and C r. On the other hand, a close relation between a hom ogeneous interm ixing at the interface and the interlayer coupling has been recently nicely demonstrated for Fe/Si/Fe [33]: the introduction of two monolayers of Fe $_{0.5}$ Si $_{0.5}$ at every Fe/Si interface brought about a much stronger coupling, as observed on the sam ples where the interm ixing took place naturally.

U sing all the above presented facts, the observed increase of the interlayer coupling can be qualitatively understood as the e ect of "phonon annealing": An ion propagating in the lattice creates pulses of hypertherm ic phonons along its trajectory. The em itted phonons increase the probability that those parts of the interfaces,

where the energetically favorable mixing has not been reached during the growth, move towards this equilibrium. Note here, that since this process at its end can produce additional energy, the phonons do not spend their energy and act just as a catalyst. In a similar way as it is observed in the Fe/Si/Fe system [33], a higher degree of the interface hom ogeneity causes higher interlayer coupling. The proposed model is rather speculative and demands further studies, which are outside the scope of this paper.

In conclusion, we have experim entally shown that antiferrom agnetic interlayer coupling of the Fe/C r/Fe(001) layered system can be modiled using ion beams after

system preparation. Depending on the thickness of the Cr-spacer and the ion beam—uence the coupling strength can either decrease or increase. Our results might open new—elds of applications of antiferrom agnetically coupled systems by laterally tayloring the coupling strength with the potential high lateral resolution of ion beams. Systems with controlled spatial variation of the local magnetization can be fabricated using this approach.

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- [1] P. Grunberg, R. Schreiber, Y. Pang, M. B. Brodsky and H. Sowers, Phys. Rev. Lett. 57, 2442 (1986).
- [2] D E. Burgler, S. O. Demokritov, P. Grunberg, M. T. Johnson, Handbook of Magnetic Materials, vol 13, Ed. K. J.H. Buschow, Elsevier, Amsterdam, 2001.
- [3] Eric E. Fullerton, D. T. Margulies, M. E. Schabes, M. Carey, B. Gumey, A. Moser, M. Best, G. Zelter, K. Rubin, and H. Rosen, M. Doemer, Appl. Phys. Lett. 77, 3806 (2000).
- [4] J. Schm alhorst, H. Bruckl, and G. Reiss, R. Kinder, G. Gieres, and J.W ecker, Appl. Phys. Lett. 77, 3456 (2000).
- [5] Q. Leng, V. Cross, R. Schafer, A. Fuss, P. Grunberg, and W. Zinn, Journ. Mag. Mat. 126, 367 (1993).
- [6] F. K lose, Ch. Rehm, D. Nagengast, H. Maletta and A. Weidinger, Phys. Rev. Lett. 78, 1150 (1997).
- [7] B. H jovarsson, J. A. Dura, P. Isberg, T. W atanabe, T. J. U dovic, G. Andersson, and C. F. Majkrzak, Phys. Rev. Lett. 79, 901 (1997).
- [8] V. Leiner, M. Au, T. Schm itte, H. Zabel, Appl Phys. A, in print 2002.
- [9] T. Aign, P. Meyer, S. Lemerle, J. P. Jamet, J. Ferre, V. Mathet, C. Chappert, J. Gierak, C. Vieu, F. Rousseaux, H. Launois, H. Bernas, Phys. Rev. Lett. 81, 5656 (1998).
- [10] P. W arin, R. Hyndman, J.N. Chapman, J. Ferre, J. P. Jam et, V. M athet, C. Chappert, Journ. Appl. Phys. 90, 3850 (2001).
- [11] J. Lohau, A. Moser, C. T. Rettner, M. E. Best, B. D. Terris, Appl. Phys. Lett. 78, 990 (2001).
- [12] R.M.H.New, R.F.W. Pease, R.L.W hite, J. Vac. Sci. Technol. B 12, 3196 (1994).
- [13] M. Ruhrig, R. Schafer, A. Hubert, R. Mosler, J. A. Wolf, S. Demokritov, and P. Grunberg, Phys. Stat. Sol. (a) 125, 635 (1991).
- [14] S.S.P.Parkin, N.More, and K.P.Roche, Phys.Rev. Lett. 64, 2304 (1990).
- [15] S.S.P.Parkin, Phys. Rev. Lett. 67, 3598 (1991).
- [16] J. Unguris, R. J. Celotta, and D. T. Pierce, Phys. Rev. Lett. 79 2734 (1997).
- [17] Y.W ang and P.M.Levy, J.L.Fry, Phys.Rev.Lett.65, 2732 (1990).

- [18] R.P.Erikson, KristlB.Hathaway and James R.Cullen, Phys.Rev.B 47, 2626 (1993).
- [19] J.C. Slonczewski, Phys. Rev. Lett. 67,3172 (1991); J.C. Slonczewski, Journ. Maq. Maq. Mat. 150, 13 (1995).
- [20] S.Demokritov, E.Tsymbal, P.G runberg, W.Zinn, I.K. Schuller, Phys.Rev.B 49, 720 (1994).
- [21] C. Chappert, H. Bernas, J. Ferre, V. Kottler, J.-P. Jam et, Y. Chen, E. Cambril, T. Devolder, F. Rousseaux, V. Mathet, and H. Launois, Science 280, 1919 (1998).
- [22] D.Ravelosona, C.Chappert, and V.M athet, H.Bemas, Appl.Phys.Lett.76, 236 (2000).
- [23] T. Mewes, R. Lopusnik, J. Fassbender, B. Hillebrands, M. Jung, D. Engel, A. Ehresmann, H. Schmoranzer Appl. Phys. Lett. 76, 1057 (2000).
- [24] A. Mougin, T. Mewes, M. Jung, D. Engel, A. Ehresmann, H. Schmoranzer, J. Fassbender, B. Hillebrands, Phys. Rev. B 63, 060409 (R) (2001).
- [25] M. Rickart, B. F. P. Roos, T. Mewes, J. Jorzick, S.O. Demokritov, B. Hillebrands, Surf. Sci. 495, 68 (2001).
- [26] E.E.Fullerton, M.J.Conover, J.E.Mattson, C.H.Sowers, and S.D.Bader, Appl. Phys. Lett. 63, 1699 (1993).
- [27] J. Ziegler, J. Biersack, and U. Littmark, The Stopping of Ions in Matter, Pergamon, New York, 1985
- [28] Slightly varying the preparation conditions, the values of the RMS roughness as well as the interlayer coupling constants and the oscillation amplitude can be changed. For simplicity only the data obtained on one and the same sample are presented in the paper.
- [29] H. Urbassek, private com munication.
- [30] B. Heinrich, J.F. Cochran, T. Monchesky, and R. Urban, Phys. Rev. B 59, 14520 (1999).
- [31] Ch. Sauer, F. K linkham m er, E. Yu. T sym bal, S. H and-schuh, Q. Leng and W. Zinn, Journ. M ag. M ag. M at. 161, 49 (1996).
- [32] M. Freyss, D. Stoe er, and H. Dreysse, Phys. Rev. B 56, 6047 (1997).
- [33] R R. Gareev, D. E. Burgler, M. Buchmeier, R. Schreiber, and P. Grunberg, submitted to Appl. Phys. Lett.